

Title:	Performance report for SiT3372, 70.656 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018

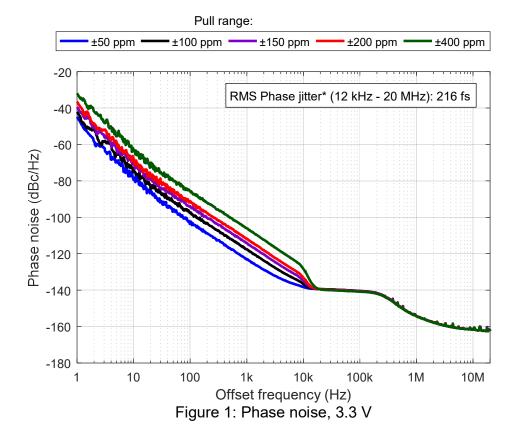
Performance report for SiT3372 - 70.656 MHz, HCSL

This performance report contains the following data:

- Phase noise
- Random phase jitter
- Output waveforms
- Pull range linearity
- Frequency stability over temperature
- Period jitter
- Duty cycle
- Rise/Fall time
- Amplitude
- Current consumption



Title:	Performance report for SiT3372, 70.656 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018



*Integrated phase jitter value applies for ±50 ppm to ±400 ppm pull ranges

Table 1: Phase noise

Phase noise dBc/Hz					
Frequency offset	Pull range (ppm)				
(Hz)	±50	±100	±150	±200	±400
1	-44.8	-42.1	-39.4	-36.4	-31.9
10	-79.5	-74.0	-70.0	-68.7	-63.6
100	-102.3	-97.2	-94.0	-91.1	-85.6
1 K	-122.9	-117.5	-114.2	-112.0	-106.0
10 K	-138.3	-136.6	-134.9	-133.2	-128.3
100 K	-140.5	-140.5	-140.6	-140.7	-140.9
1 M	-154.2	-154.2	-154.3	-154.3	-154.4
10 M	-161.7	-161.8	-161.7	-161.7	-161.8
20 M	-162.5	-162.5	-162.4	-162.5	-162.6

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 2 of 10



Title:	Performance report for SiT3372, 70.656 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	

Table 2: Integrated Phase jitter

Parameter	Units	Pull range (ppm)
Parameter	Utills	±50 to ±400
Integrated Phase jitter (1.875 MHz - 20 MHz)	fs, rms	119
Integrated Phase jitter (12 kHz - 20 MHz)	fs, rms	216



Title:	Performance report for SiT3372, 70.656 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	



Figure 2: Output waveform, 2.5 V



Figure 3: Output waveform, 3.3 V

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 4 of 10



Title:	Performance report for SiT3372, 70.656 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018

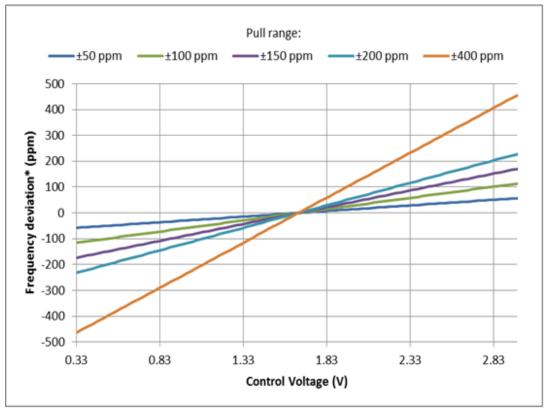


Figure 4: Frequency pull characteristic



Title:	Performance report for SiT3372, 70.656 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	

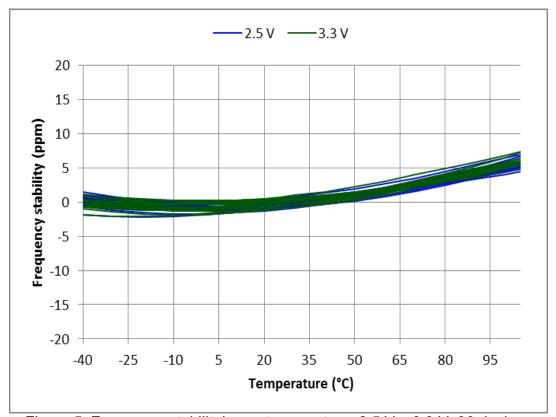


Figure 5: Frequency stability* over temperature, 2.5 V – 3.3 V, 30 devices

*SiT3372 frequency stability is independent of output frequency.



Title:	Performance report for SiT3372, 70.656 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018

Table 3: Summary performance data

Parameter	Units	Voltage		
Farameter	UTILIS	2.5 V	3.3 V	
Period jitter	ps, rms	1.02	1.06	
Period jitter (sample size 10,000 cycles)	ps, pk-pk	7.99	7.80	
Duty cycle	%	50.0	50.0	
Rise time (20% - 80%)	ps	369	365	
Fall time (80% - 20%)	ps	367	364	
Differential voltage swing	V	1.37	1.44	
Current consumption (no load, output enabled)	mA	82.3	82.5	
Current consumption (no load, output disabled)	mA	57.5	57.5	



Title:	Performance report for SiT3372, 70.656 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	

Test description

Conditions:

- Frequency: 70.656 MHz

- VDD: 2.5 V, 3.3 V

- Pull range: ±50 ppm, ±100 ppm, ±150 ppm, ±200 ppm, ±400 ppm

- Temperature: 25 °C

Equipment:

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz,	Period jitter, output amplitude, rise/fall time,
20 Gsps)	duty cycle
Keysight 5052B Signal Source	Phase noise, integrated phase jitter
Analyzer	
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency



Title:	Performance report for SiT3372, 70.656 MHz, HCSL				
Type:	Performance report	Rev:	1.2		
Orig:		Date:	September 07, 2018		

Setup

Waveform

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 30 Ω series and 50 Ω to GND. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 6 shows test setup diagram for waveform parameters measurement.

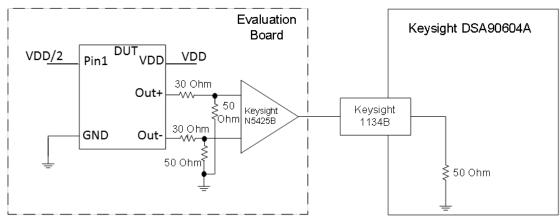


Figure 6. Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

Period Jitter

For period jitter measurement output is terminated with 30 Ω series and 50 Ω to GND at the input of hi-speed comparator (ADCMP581). AC coupled comparator's output is connected to oscilloscope channel. Figure 7 shows test setup diagram for period jitter measurement.

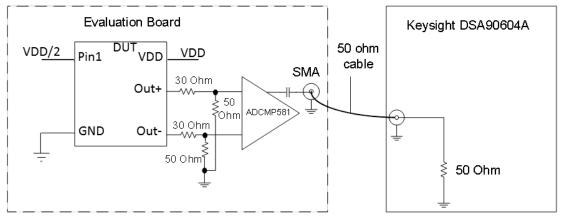


Figure 7. Test setup for measuring period jitter

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 9 of 10

	Title:	Performance report for SiT3372, 70.656 MHz, HCSL		
Si Time	Type:	Performance report	Rev:	1.2
	Orig:		Date:	September 07, 2018

Phase noise

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Output is also terminated with 30 Ω series at the source side. Figure 8 shows test setup diagram for phase noise measurement.

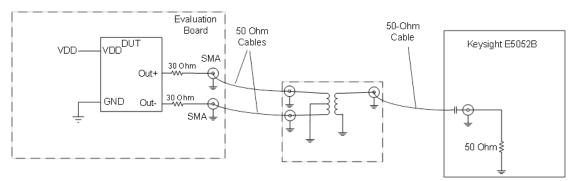


Figure 8. Test setup for measuring phase noise.

Current consumption

For Current consumption measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.